Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	. 2	"6714902"	US-PGPUB; USPAT; EPO; DERWENT	OR	OFF	2005/07/20 13:20
L2	15	("4527249" "4722071" "4924430" "5095454" "5191541" "5355321" "5600787" "5648909" "5657239" "5805459" "5946475" "6026222" "6086626" "6097884" "6286126").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/07/20 14:00
L3	768	feedback near cycle	US-PGPUB; USPAT; EPO; DERWENT	OR	OFF	2005/07/20 14:00
L4	547	L3 and @ad<"20010901"	US-PGPUB; USPAT; EPO; DERWENT	OR	OFF	2005/07/20 14:03
L5	0	L4 and 7%%/\$.ccls.	US-PGPUB; USPAT; EPO; DERWENT	OR	OFF	2005/07/20 14:02
L6	513	L3 and @ad<"20010901"	US-PGPUB; USPAT	OR	OFF	2005/07/20 14:03
L7	153	L6 and sensiti\$6	US-PGPUB; USPAT	OR	OFF	2005/07/20 14:06
L8	720	714/738.ccls.	US-PGPUB; USPAT; EPO; DERWENT	OR	OFF	2005/07/20 14:08
L9	604	L8 and @ad<"20010901"	US-PGPUB; USPAT; EPO; DERWENT	OR	OFF	2005/07/20 14:09
L10	427	L9 and (cycl\$2 or loop\$1 or feedback or sequential)	US-PGPUB; USPAT; EPO; DERWENT	OR	OFF	2005/07/20 14:10
L13	8	"5910958"	USPAT	OR	OFF	2005/07/20 15:14
L14	7	("5910958").URPN.	USPAT	OR	OFF	2005/07/20 15:23
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